

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

## TC74HC375AP, TC74HC375AF, TC74HC375AFN

### 4-Bit D Type Latch

The TC74HC375A is a high speed CMOS D-TYPE LATCH fabricated with silicon gate C<sup>2</sup>MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

It contains two groups of 2-bit latches controlled by an enable input (G1·2 or G3·4) and each group can be used in different circuits.

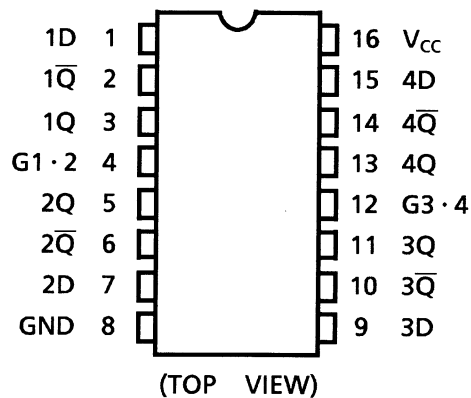
Data applied to the data inputs are transferred to the Q and  $\bar{Q}$  outputs when the enable inputs is high. When the enable input is low, the outputs are not affected.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

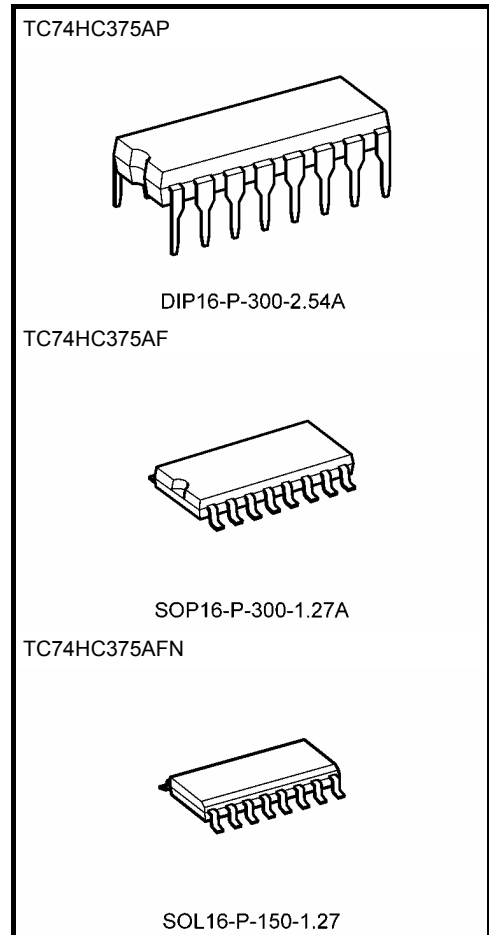
### Features

- High speed:  $t_{pd} = 14 \text{ ns}$  (typ.) at  $V_{CC} = 5 \text{ V}$
- Low power dissipation:  $I_{CC} = 4 \mu\text{A}$  (max) at  $T_a = 25^\circ\text{C}$
- High noise immunity:  $V_{NIH} = V_{NIL} = 28\% V_{CC}$  (min)
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance:  $|I_{OH}| = I_{OL} = 4 \text{ mA}$  (min)
- Balanced propagation delays:  $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range:  $V_{CC} \text{ (opr)} = 2 \text{ to } 6 \text{ V}$
- Pin and function compatible with 74LS375

### Pin Assignment



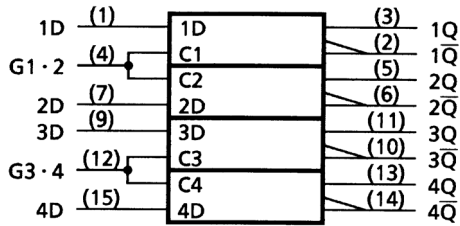
Note: xxxFN (JEDEC SOP) is not available in Japan.



### Weight

DIP16-P-300-2.54A	: 1.00 g (typ.)
SOP16-P-300-1.27A	: 0.18 g (typ.)
SOL16-P-150-1.27	: 0.13 g (typ.)

## IEC Logic Symbol

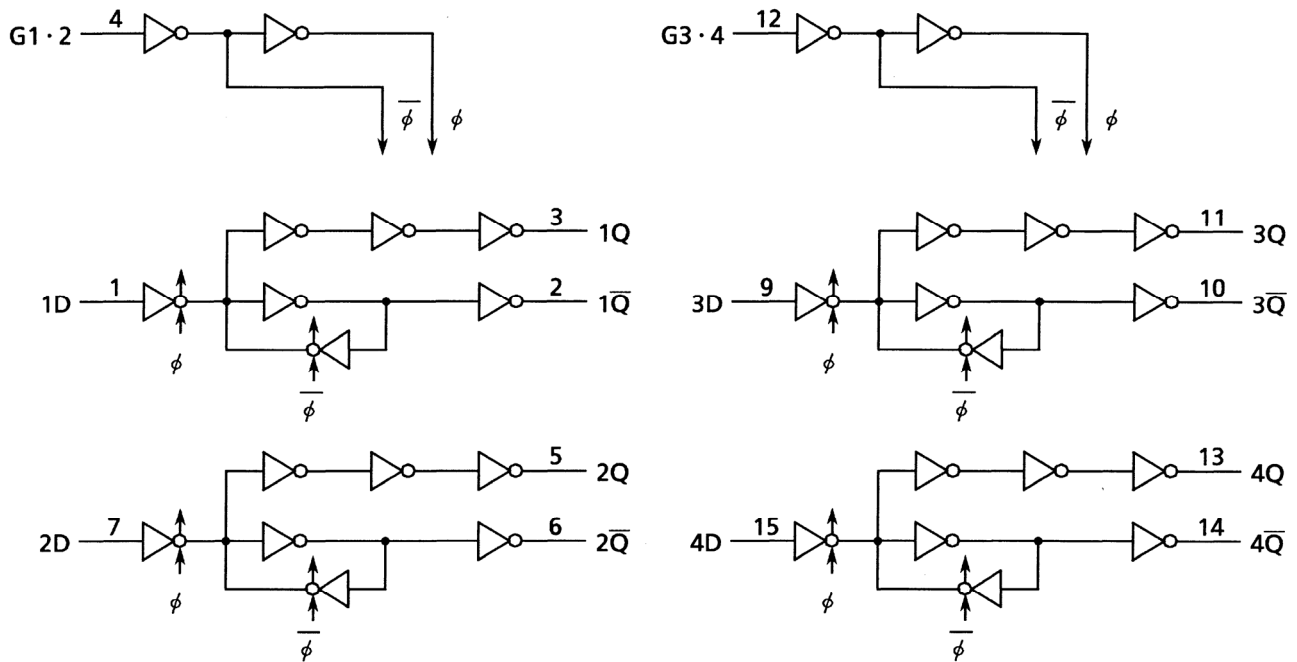


## Truth Table

Inputs		Outputs		Function
D	G	Q	$\bar{Q}$	
L	H	L	H	—
H	H	H	L	—
X	L	Qn	$\bar{Q}n$	Latch

X: Don't care

## System Diagram



## Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	$V_{CC}$	-0.5 to 7	V
DC input voltage	$V_{IN}$	-0.5 to $V_{CC} + 0.5$	V
DC output voltage	$V_{OUT}$	-0.5 to $V_{CC} + 0.5$	V
Input diode current	$I_{IK}$	$\pm 20$	mA
Output diode current	$I_{OK}$	$\pm 20$	mA
DC output current	$I_{OUT}$	$\pm 25$	mA
DC $V_{CC}$ /ground current	$I_{CC}$	$\pm 50$	mA
Power dissipation	$P_D$	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	$T_{stg}$	-65 to 150	$^{\circ}C$

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of  $T_a = -40$  to  $65^{\circ}C$ . From  $T_a = 65$  to  $85^{\circ}C$  a derating factor of  $-10$  mW/ $^{\circ}C$  shall be applied until 300 mW.

## Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	$V_{CC}$	2 to 6	V
Input voltage	$V_{IN}$	0 to $V_{CC}$	V
Output voltage	$V_{OUT}$	0 to $V_{CC}$	V
Operating temperature	$T_{opr}$	-40 to 85	$^{\circ}C$
Input rise and fall time	$t_r, t_f$	0 to 1000 ( $V_{CC} = 2.0$ V) 0 to 500 ( $V_{CC} = 4.5$ V) 0 to 400 ( $V_{CC} = 6.0$ V)	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

## Electrical Characteristics

### DC Characteristics

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40 to 85°C		Unit	
				V <sub>CC</sub> (V)	Min	Typ.	Max	Min		Max
High-level input voltage	V <sub>IH</sub>	—		2.0	1.50	—	—	1.50	—	V
				4.5	3.15	—	—	3.15	—	
				6.0	4.20	—	—	4.20	—	
Low-level input voltage	V <sub>IL</sub>	—		2.0	—	—	0.50	—	0.50	V
				4.5	—	—	1.35	—	1.35	
				6.0	—	—	1.80	—	1.80	
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -20 μA	2.0	1.9	2.0	—	1.9	—	V
				4.5	4.4	4.5	—	4.4	—	
			I <sub>OH</sub> = -4 mA	4.5	4.18	4.31	—	4.13	—	
			I <sub>OH</sub> = -5.2 mA	6.0	5.68	5.80	—	5.63	—	
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 20 μA	2.0	—	0.0	0.1	—	0.1	V
				4.5	—	0.0	0.1	—	0.1	
			I <sub>OL</sub> = 4 mA	4.5	—	0.17	0.26	—	0.33	
			I <sub>OL</sub> = 5.2 mA	6.0	—	0.18	0.26	—	0.33	
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0	—	—	±0.1	—	±1.0	μA
Quiescent supply current	I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		6.0	—	—	4.0	—	40.0	μA

### Timing Requirements (input: t<sub>r</sub> = t<sub>f</sub> = 6 ns)

Characteristics	Symbol	Test Condition		Ta = 25°C		Ta = -40 to 85°C	Unit	
				V <sub>CC</sub> (V)	Typ.	Limit		Limit
Minimum pulse width (G)	t <sub>W</sub> (H)	—		2.0	—	75	95	ns
				4.5	—	15	19	
				6.0	—	13	16	
Minimum set-up time	t <sub>s</sub>	—		2.0	—	75	95	ns
				4.5	—	15	19	
				6.0	—	13	16	
Minimum hold time	t <sub>h</sub>	—		2.0	—	0	0	ns
				4.5	—	0	0	
				6.0	—	0	0	

### AC Characteristics ( $C_L = 15 \text{ pF}$ , $V_{CC} = 5 \text{ V}$ , $T_a = 25^\circ\text{C}$ , input: $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Output transition time	$t_{TLH}$ $t_{THL}$	—	—	4	8	ns
Propagation delay time (D-Q, $\bar{Q}$ )	$t_{pLH}$ $t_{pHL}$	—	—	14	20	ns
Propagation delay time (G-Q, $\bar{Q}$ )	$t_{pLH}$ $t_{pHL}$	—	—	13	20	ns

### AC Characteristics ( $C_L = 50 \text{ pF}$ , input: $t_r = t_f = 6 \text{ ns}$ )

Characteristics	Symbol	Test Condition	$T_a = 25^\circ\text{C}$			$T_a = -40 \text{ to } 85^\circ\text{C}$		Unit	
			$V_{CC} \text{ (V)}$	Min	Typ.	Max	Min		Max
Output transition time	$t_{TLH}$ $t_{THL}$	—	2.0	—	30	75	—	95	ns
			4.5	—	8	15	—	19	
			6.0	—	7	13	—	16	
Propagation delay time (D-Q, $\bar{Q}$ )	$t_{pLH}$ $t_{pHL}$	—	2.0	—	60	120	—	150	ns
			4.5	—	17	24	—	30	
			6.0	—	15	20	—	26	
Propagation delay time (G-Q, $\bar{Q}$ )	$t_{pLH}$ $t_{pHL}$	—	2.0	—	56	120	—	150	ns
			4.5	—	16	24	—	30	
			6.0	—	14	20	—	26	
Input capacitance	$C_{IN}$	—	—	5	10	—	10	pF	
Power dissipation capacitance	$C_{PD}$ (Note)	—	—	55	—	—	—	pF	

Note:  $C_{PD}$  is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

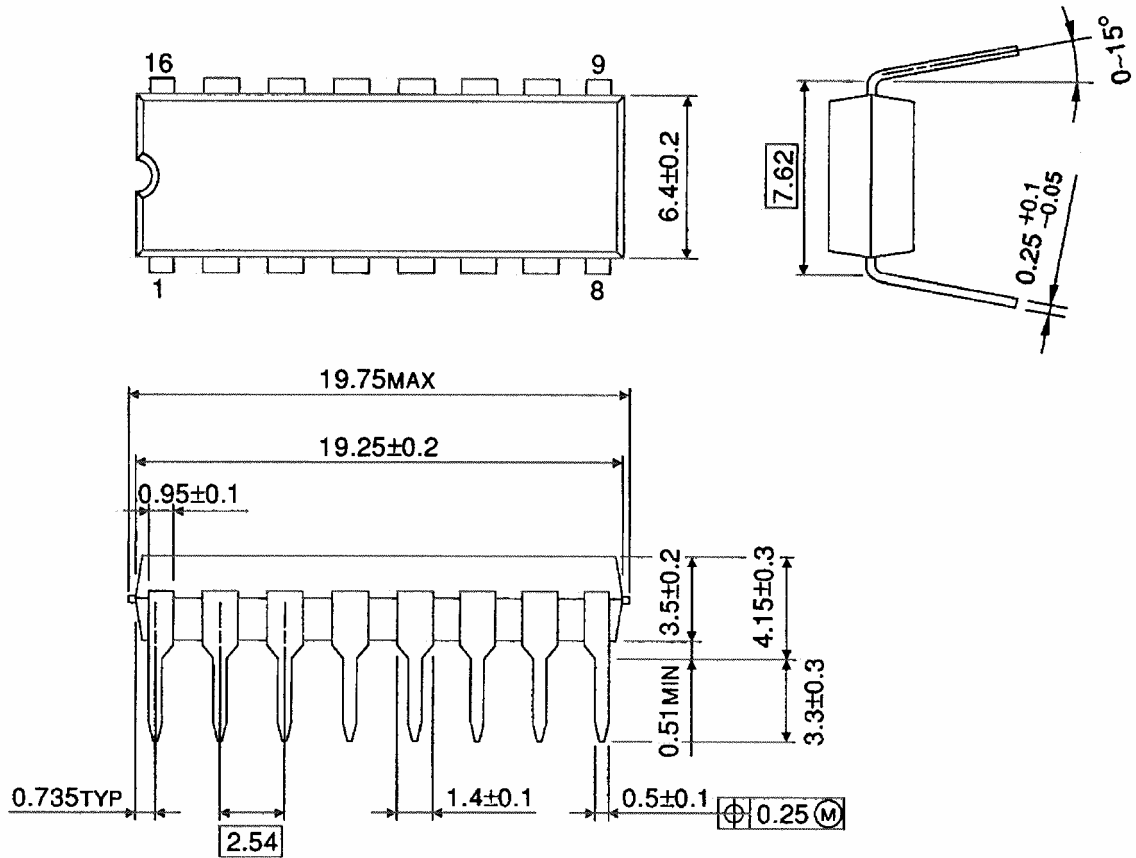
Average operating current can be obtained by the equation:

$$I_{CC} \text{ (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4 \text{ (per latch)}$$

## Package Dimensions

DIP16-P-300-2.54A

Unit : mm

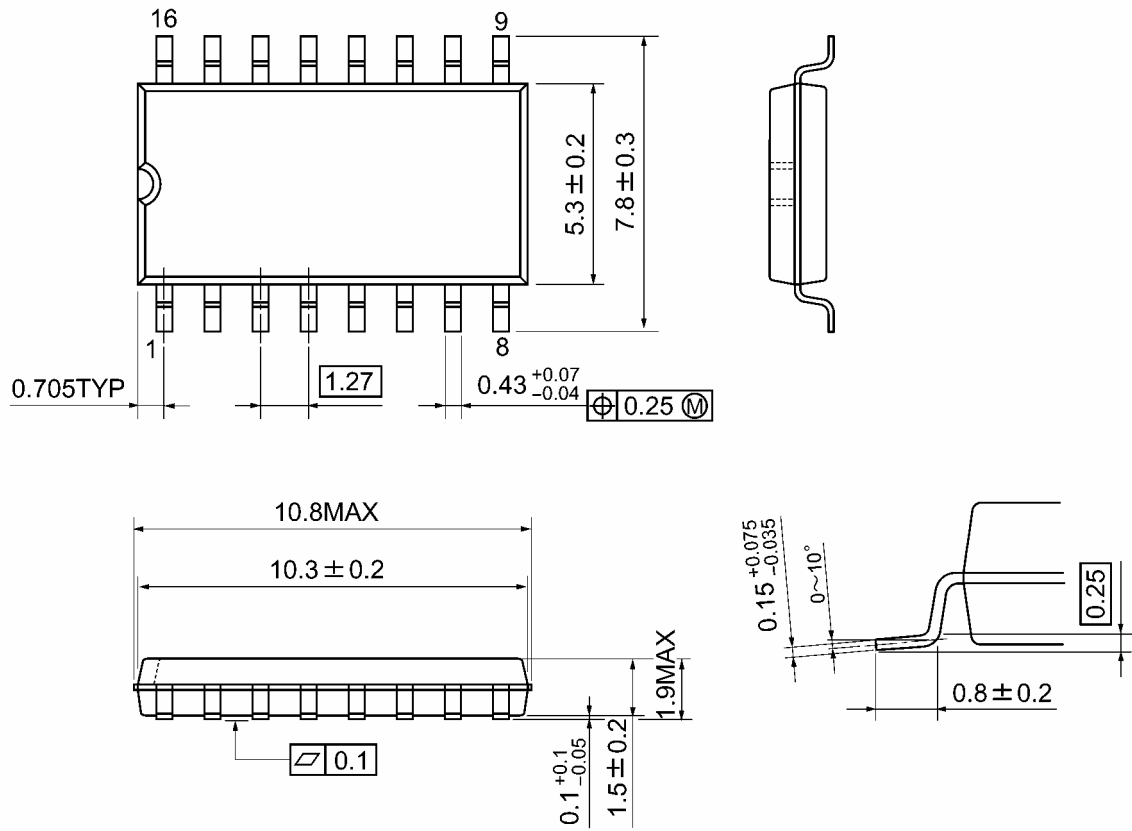


Weight: 1.00 g (typ.)

**Package Dimensions**

SOP16-P-300-1.27A

Unit: mm

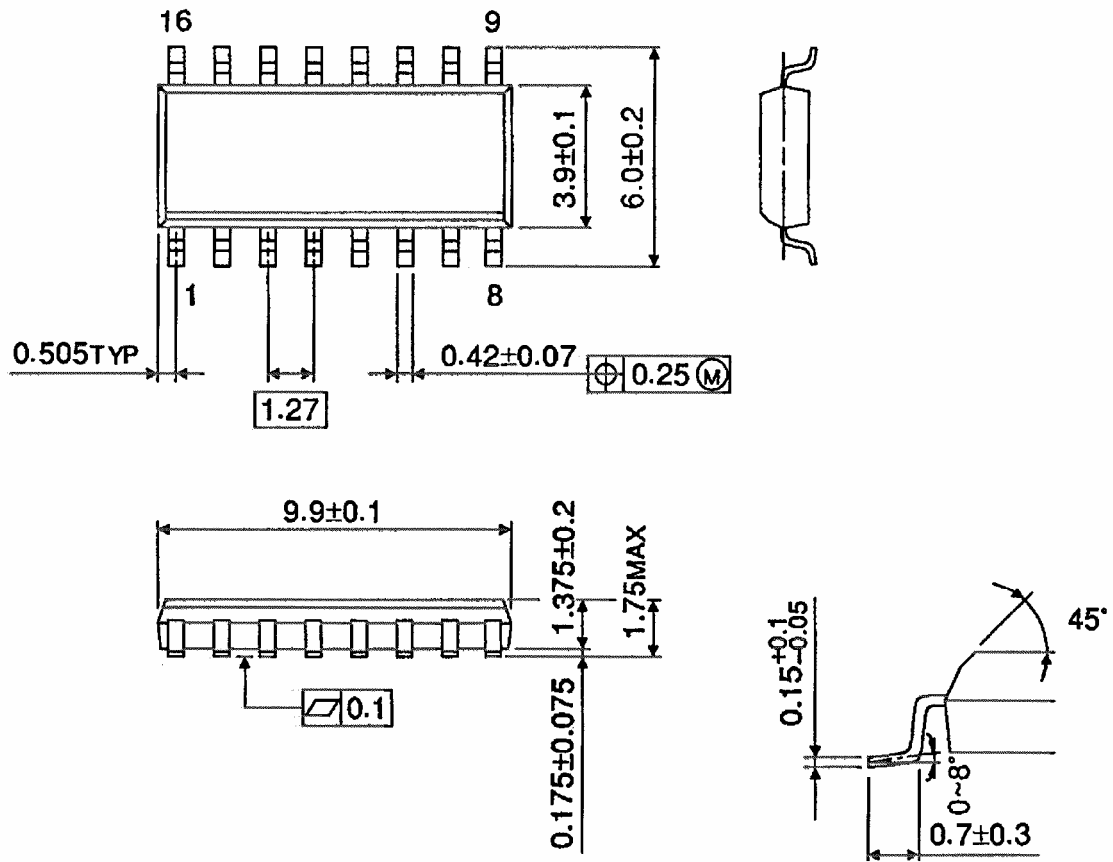


Weight: 0.18 g (typ.)

Package Dimensions (Note)

SOL16-P-150-1.27

Unit : mm



Note: This package is not available in Japan.

Weight: 0.13 g (typ.)



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20070701-EN GENERAL

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